

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology
- ★ 100% EAS Guaranteed

Product Summary

RoHS

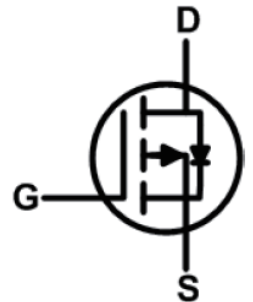
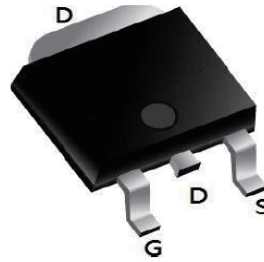
BVDSS	RDSON	ID
-30V	6mΩ	-80A

Description

The 80P03 is the high cell density trenched P-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The 80P03 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

TO252 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-to-Source Voltage	-30	V
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> = 25°C	-80
		T <sub>C</sub> = 100°C	-42
I <sub>DM</sub>	Pulsed Drain Current <sup>(1)</sup>	-175	A
E <sub>AS</sub>	Single Pulsed Avalanche Energy <sup>(2)</sup>	31	mJ
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C	31.2
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient <sup>(3)</sup>	43	°C/W
R <sub>θJC</sub>	Thermal Resistance, Junction to Case	4	
T <sub>J</sub> , T <sub>STG</sub>	Junction & Storage Temperature Range	-55 to 150	°C
I <sub>AS</sub>	Avalanche Current	-25	A

**Electrical Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise specified)**

Symbol	Parameter	Test condition	Min.	Typ.	Max.	Units	
<b>Static Characteristics</b>							
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	-30	-	-	V	
$I_{GSS}$	Gate-body Leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	$\pm 100$	nA	
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 85V, V_{GS} = 0V$	$T_J = 25^\circ\text{C}$	-	-	-1	$\mu A$
			$T_J = 55^\circ\text{C}$	-	-	-5	$\mu A$
$V_{GS(th)}$	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	-1	-1.6	-2.5	V	
$R_{DS(on)}$	Drain-Source on-Resistance <sup>2</sup>	$V_{GS} = -10V, I_D = -12A$	-	6	8.8	m $\Omega$	
		$V_{GS} = -4.5V, I_D = -8A$	-	9	14		
$g_{fs}$	Forward Transconductance <sup>4</sup>	$V_{DS} = -5V, I_D = -20A$	-	28	-	S	
<b>Dynamic Characteristics<sup>5</sup></b>							
$C_{iss}$	Input Capacitance	$V_{DS} = -15V, V_{GS} = 0V,$ $f = 1\text{MHz}$	-	4320	-	pF	
$C_{oss}$	Output Capacitance		-	529	-	pF	
$C_{rss}$	Reverse Transfer Capacitance		-	487	-	pF	
<b>Switching Characteristics<sup>5</sup></b>							
$R_g$	Gate Resistance	$f = 1\text{MHz}$	-	4	-	$\Omega$	
$Q_g$	Total Gate Charge	$V_{GS} = -10V, V_{DS} = -15V,$ $I_D = -15A$	-	45	-	nC	
$Q_{gs}$	Gate-Source Charge		-	8.5	-	nC	
$Q_{gd}$	Gate-Drain Charge		-	12.8	-	nC	
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = -10V, V_{DD} = -15V,$ $R_G = 2.5\Omega, I_D = -15A$	-	16.5	-	ns	
$t_r$	Rise Time		-	51.8	-	ns	
$t_{d(off)}$	Turn-off Delay Time		-	37.1	-	ns	
$t_f$	Fall Time		-	8.2	-	ns	
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F = 20A, di/dt = 100A/\mu S$	-	69	-	ns	
$Q_{rr}$	Body Diode Reverse Recovery Charge		-	141	-	nC	
<b>Drain-Source Body Diode Characteristics</b>							
$V_{SD}$	Diode Forward Voltage <sup>2</sup>	$I_S = -1A, V_{GS} = 0V$	-	-	-1	V	
$I_S$	Continuous Source Current	$V_G = V_D = 0V, \text{Force Current}$	-	-	-80	A	

- Notes:
- The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
  - The data tested by pulsed, pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$
  - The EAS data shows Max. rating. The test condition is  $V_{DD} = -25V, V_{GS} = -10V, L = 0.1\text{mH}, I_{AS} = -25A$
  - The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
  - The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.

Typical Performance Characteristics

Figure 1: Output Characteristics

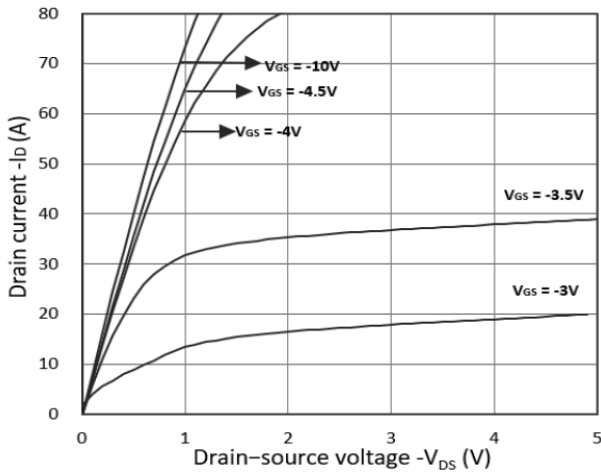


Figure 2: Transfer Characteristics

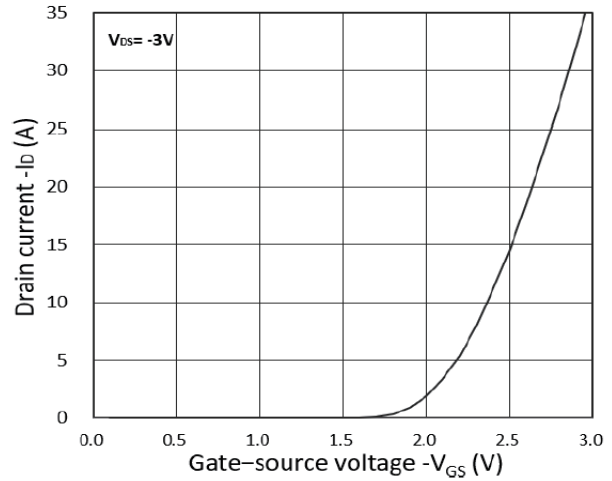


Figure 3: Forward Characteristics of Reverse

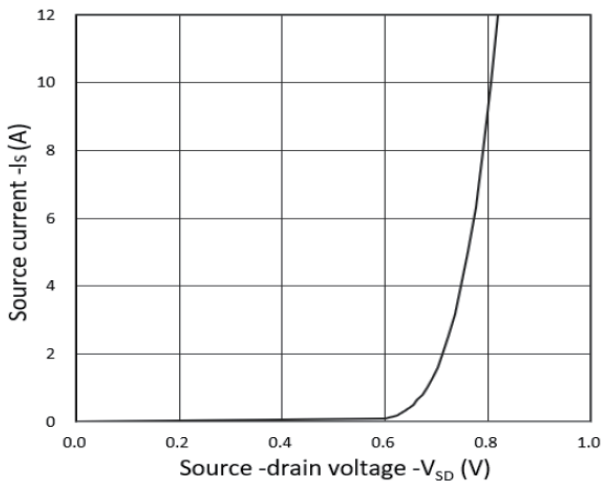


Figure 4: Gate Charge Characteristics

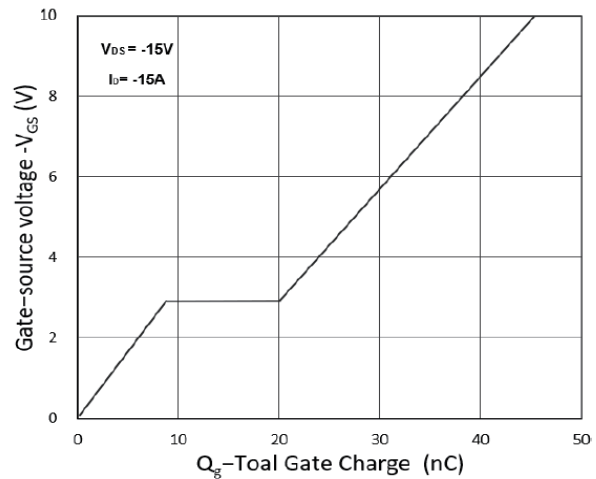


Figure 5: R\_DS(on) vs. V\_GS

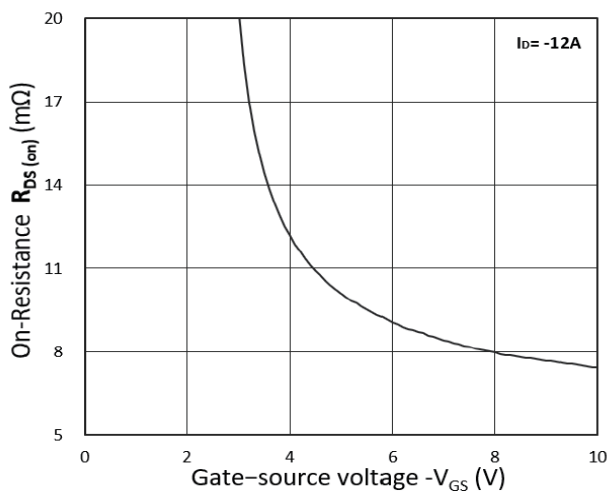
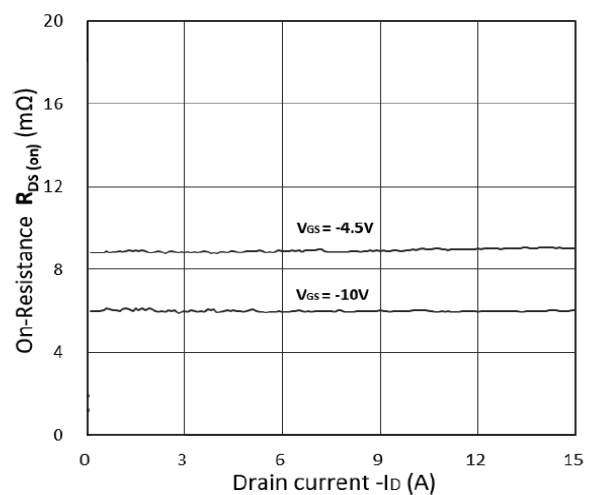


Figure 6: R\_DS(on) vs. I\_D



Typical Performance Characteristics

Figure 7: Capacitance Characteristics

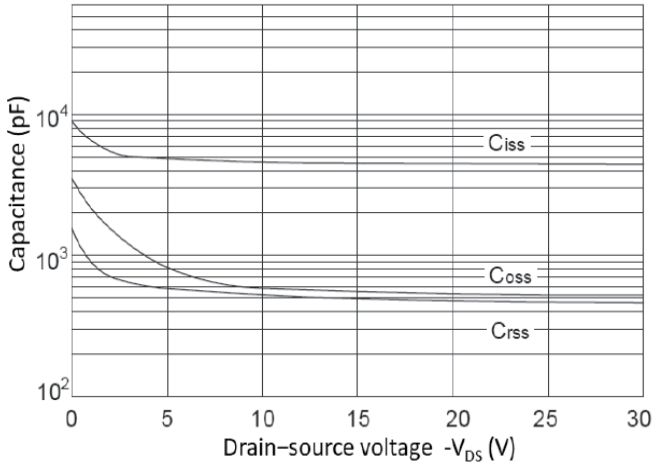


Figure 8: Safe Operating Area

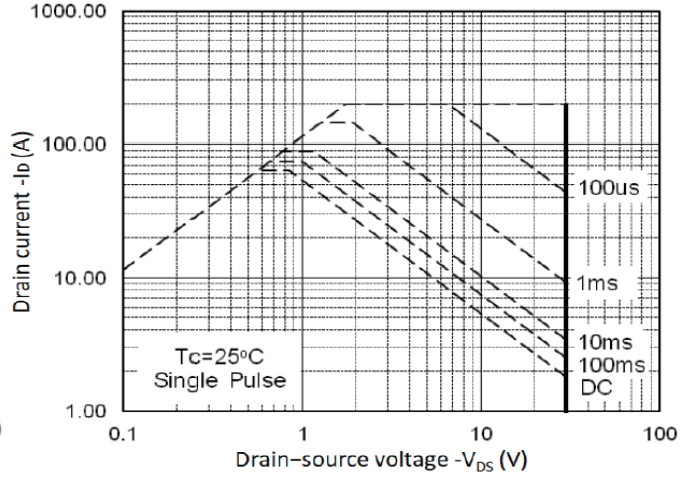


Figure 9: Normalized Maximum Transient

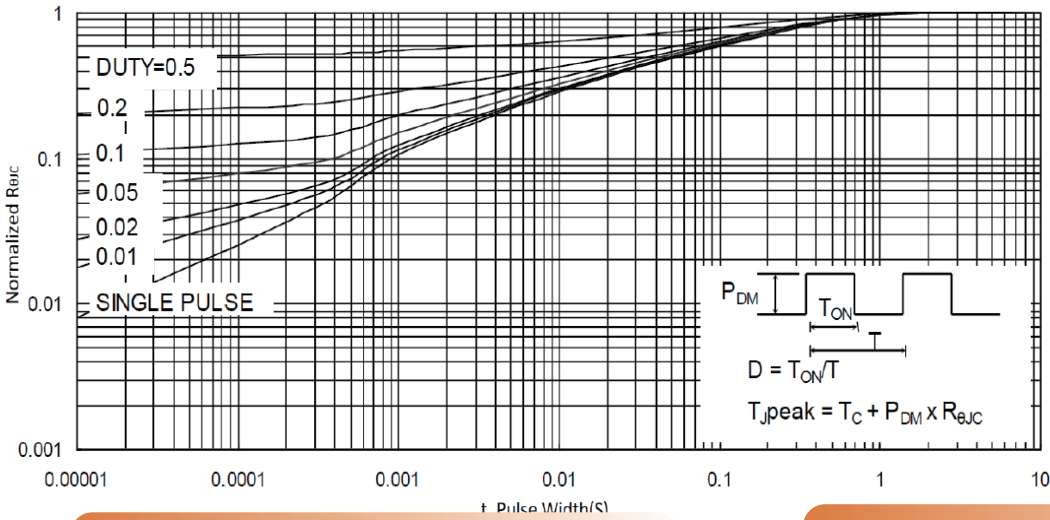


Figure 10: Switching Time Waveform

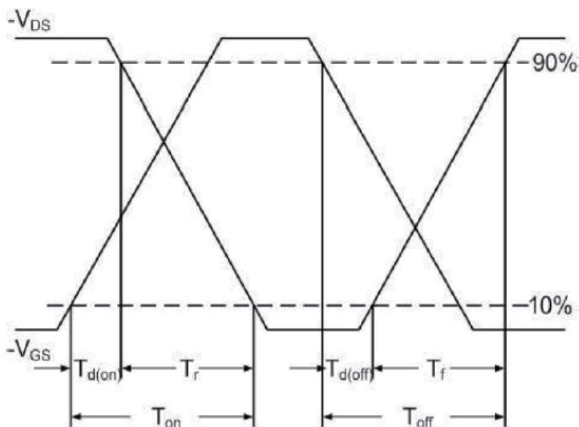
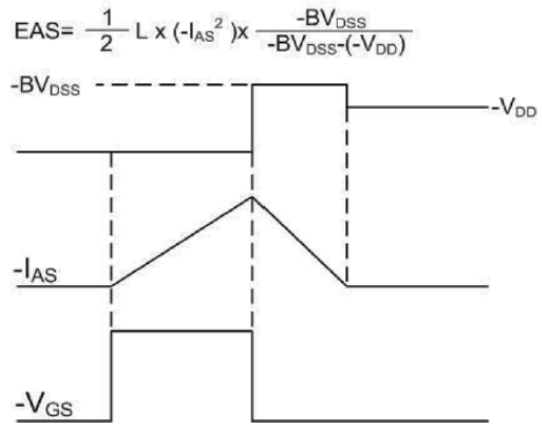
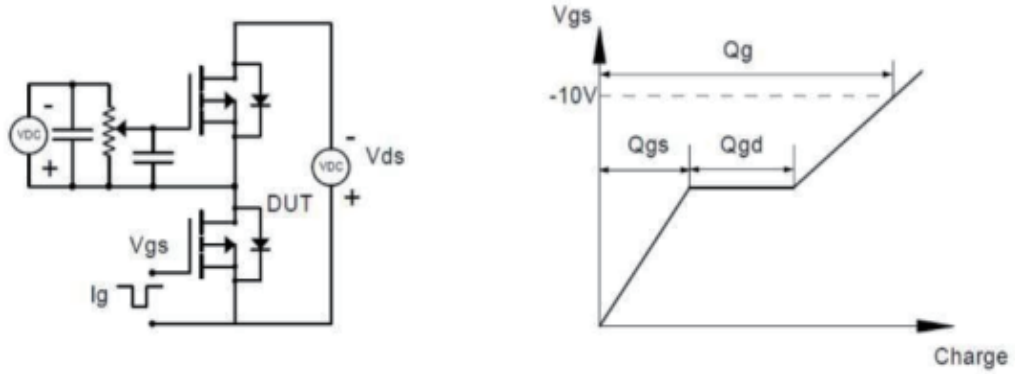


Figure 11: Unclamped Inductive Switching

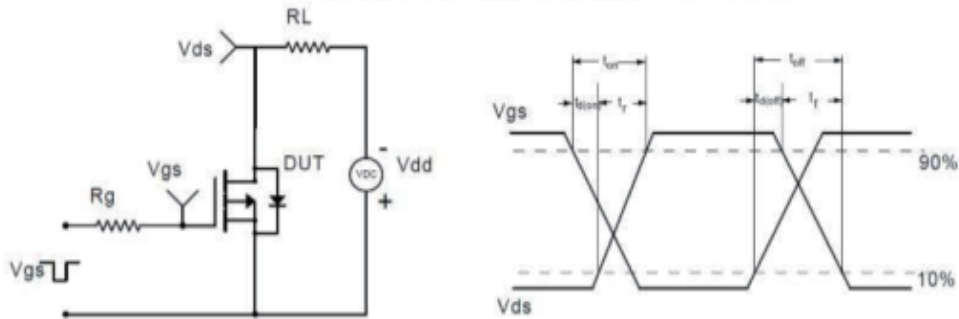


Test Circuit

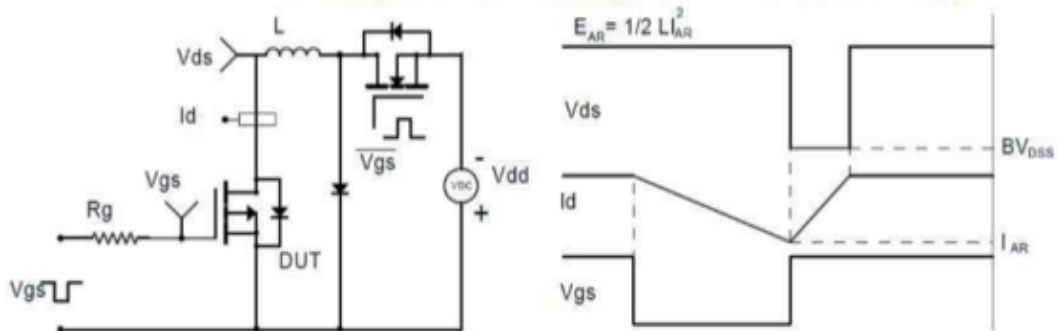
Gate Charge Test Circuit & Waveform



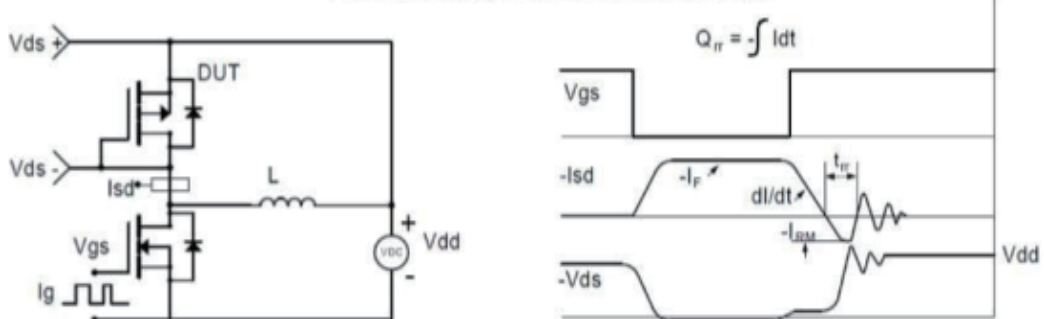
Resistive Switching Test Circuit & Waveforms



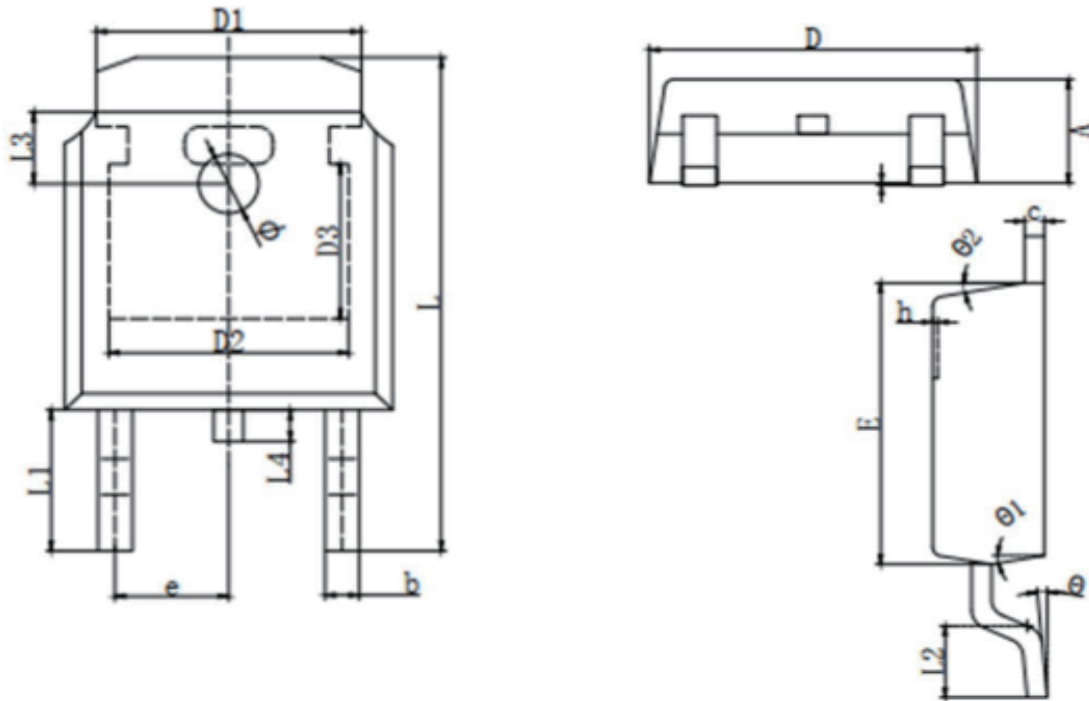
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



TO-252 Package outline



SYMBOL	MILLIMETER		SYMBOL	MILLIMETER	
	MIN	MAX		MIN	MAX
A	2.200	2.400	h	0.000	0.200
A1	0.000	0.127	L	9.900	10.30
b	0.640	0.740	L1	2.988 REF	
c	0.460	0.580	L2	1.400	1.700
D	6.500	6.700	L3	1.600 REF	
D1	5.334 REF		L4	0.600	1.000
D2	4.826 REF		$\phi$	1.100	1.300
D3	3.166 REF		$\theta$	0°	8°
E	6.000	6.200	$\theta 1$	9° TYP2	
e	2.286 TYP		$\theta 2$	9° TYP	